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CERTIFICATE OF MAILING
37 C.F.R. § 1.8

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date below:

July 21, 2004
Date

Mary Paul
Signature

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

HARTMUT RUELKE
JOERG HOHAGE
THOMAS WERNER
MICHAEL KIENE

Serial No.: 10/716,681

Filed: November 19, 2003

For: NITROGEN-ENRICHED LOW-K
BARRIER LAYER FOR A COPPER
METALLIZATION LAYER

Group Art Unit: 2812

Examiner: Unknown

Atty. Dkt. No.: 2000.108700/DE0363

Customer No.: 23720

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56, it is respectfully requested that this Information Disclosure Statement be entered and the documents listed on attached Form PTO-1449 be considered by the Examiner and made of record. Copies of the listed foreign patent documents required by 37 C.F.R. § 1.98(a)(2) are enclosed for the convenience of the Examiner. Because the filing date of the present application is after June 30, 2003, copies of the listed U.S. patents are not included.

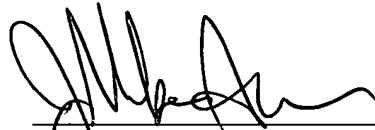
In accordance with 37 C.F.R. §§ 1.97(g),(h), this Information Disclosure Statement is not to be construed as a representation that a search has been made, and is not to be construed to be an admission that the information cited is, or is considered to be, material to patentability as defined in 37 C.F.R. § 1.56(b).

In accordance with 37 C.F.R. § 1.97(e)(1), Applicants hereby certify that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the present statement, as evidenced by the date of the enclosed letter from our associate in Germany.

Applicants respectfully request that the listed documents be made of record in the present case.

Respectfully submitted,

WILLIAMS, MORGAN & AMERSON
CUSTOMER NUMBER 23720



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Date: July 21, 2004

Form PTO-1449 (modified)

Atty. Docket No.
2000.108700/DE0349Serial No.
10/716,681

List of Patents and Publications for Applicant's

Applicant
Hartmut Ruelke, Joerg Hohage, Thomas Werner and
Michael Kiene

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Filing Date:
November 19, 2003Group:
2812U.S. Patent Documents
See Page 1Foreign Patent Documents
See Page 1Other Art
See Page 1

U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.
	A1	2002/0119250 A1	8/29/02	Campana <i>et al.</i>	427	255.28	
	A2	2003/0045098 A1	3/06/03	Verhaverbeke <i>et al.</i>	438	689	
	A3	2003/0077916 A1	8/24/03	Xu <i>et al.</i>	438	778	
	A4						
	A5						

Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B1	EP 1 061 156 A2	12/20/00	Europe	C23C	16/56	Yes
	B2	EP 1 077 479 A1	2/21/01	Europe	H01L	21/316	Yes
	B3						

Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
	C1	Kim <i>et al.</i> , "Breakdown Phenomena in MIS Structure," <i>Proc. Of 3rd Int'l Conf. on Properties and Application of Dielectric Materials</i> , Tokyo, Japan, pp. 164-168, July 8-12, 1991.
	C2	Shanware <i>et al.</i> , "Reliability evaluation of HiSiON gate dielectric film with 12.8 Å SiO ₂ equivalent thickness," <i>IEEE</i> , pp. 6.6.1-6.6.4, 2001.
	C3	Abadeer <i>et al.</i> , "Key measurements of ultrathin gate dielectric reliability and in-line monitoring," <i>IBM J. Res. Develop.</i> , 43:407-16, 1999.

EXAMINER:

DATE CONSIDERED:

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

INFORMATION DISCLOSURE STATEMENT — PTO-1449 (MODIFIED)

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2000.108700/14

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001-713-9347011

Handwritten notes and stamps:
"Not Registered"
"Art in DE OA"
"8-604"
Signature of Anton Pfau

IHR ZEICHEN / YOUR REF.

AMD Ref. No. DE0363

UNSER ZEICHEN / OUR REF.

P35163AP088we

DATUM / DATE

06.07.2004

Re: German Patent Application No. 103 19 136.4-33
Applicant: ADVANCED MICRO DEVICES, INC.

Dear Mike:

DOCKETING DEPT.

JUL 13 2004

WILLIAMS, MORGAN & AMERSON

Regarding the above-referenced German patent application, please be informed that we have received a first Office Action from the GPTO, to which a response is due by the extended term of **July 20, 2004**.

Please find enclosed copies of the translated Official Communication, our report letter to Paul Drake, and copies of the cited prior art. We will discuss the further procedure with both AMD legal and the inventor and will then inform you again of our filed response.

Very truly yours,

Signature of Anton Pfau
(Anton Pfau)

Encls: Translation of Official Communication and copies of cited prior art
Copy of letter to Paul Drake

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